## Search Notes

| Application/Contr | ol No. | Applicant(s)/Patent Under Reexamination |
|-------------------|--------|---|
| 10525966          |        | SHOJI ET AL.                            |
| Examiner          |        | Art Unit                                |
| Flores, Leon      |        | 2611                                    |

| SEARCHED |                    |           |          |
|----------|--------------------|-----------|----------|
| Class    | Subclass           | Date      | Examiner |
| 375      | 132, 133, 135, 136 | 11/5/2007 | LF       |

| SEARCH NOTES  |            |          |  |
|---|------------|----------|--|
| Search Notes  | Date       | Examiner |  |
| Consulted with SPE David Payne in regards to the patentability of the | 11/13/2007 | LF       |  |
| claims.   |            |          |  |
| Checked for possible double patenting.                                | 10/20/2007 | LF       |  |
| Consulted with SPE David Payne in regards to the amendments.          | 6/27/2008  | LF       |  |
| Consulted with SPE David Payne in regards to the RCE.                 | 12/5/2008  | LF       |  |
| Consulted with SPE Shuwang Liu in regards to the references used to   | 5/29/2009  | LF       |  |
| reject the claims.  |            |          |  |
| Consulted with SPE David Payne in regards to the new ground of        | 11/25/2009 | LF       |  |
| rejection.  |            |          |  |
| Consulted with SPE David Payne in regards to the amendments.          | 5/17/2010  | LF       |  |

| INTERFERENCE SEARCH |                                   |           |          |  |
|---------------------|-----------------------------------|-----------|----------|--|
| Class               | Subclass                          | Date      | Examiner |  |
| 375                 | 130, 132, 133, 134, 135, 136, 137 | 5/17/2010 | LF       |  |

| /L. F./<br>Examiner.Art Unit 2611 |  |
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U.S. Patent and Trademark Office Part of Paper No. : 20100517